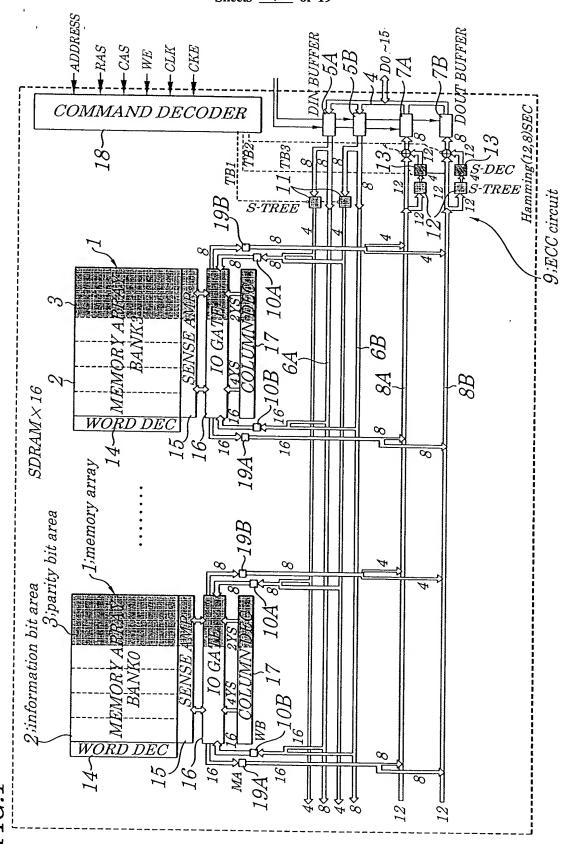
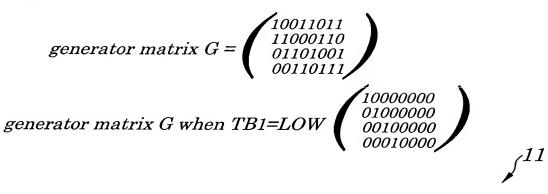
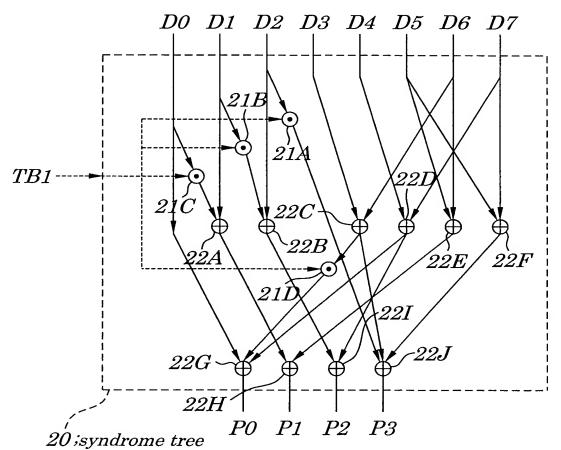
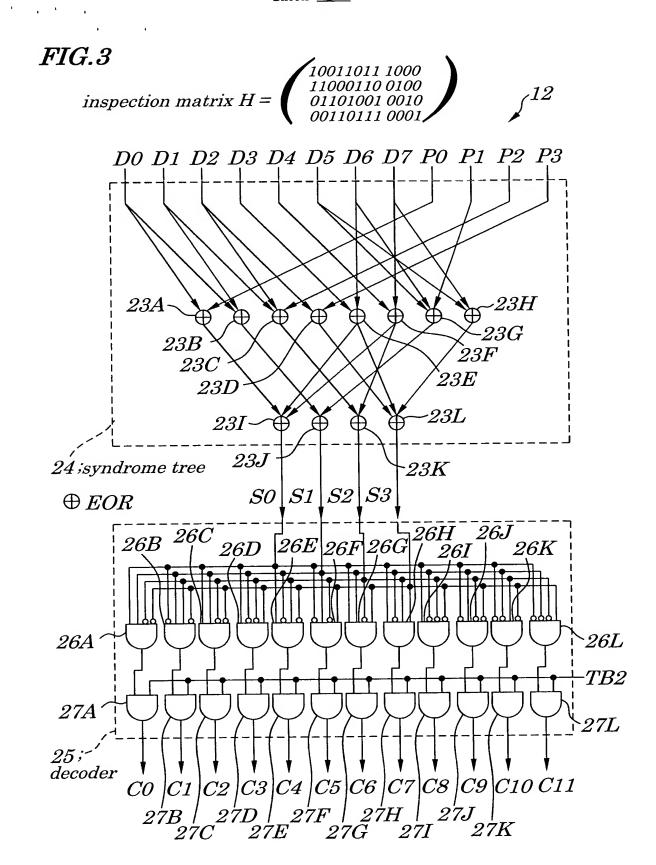
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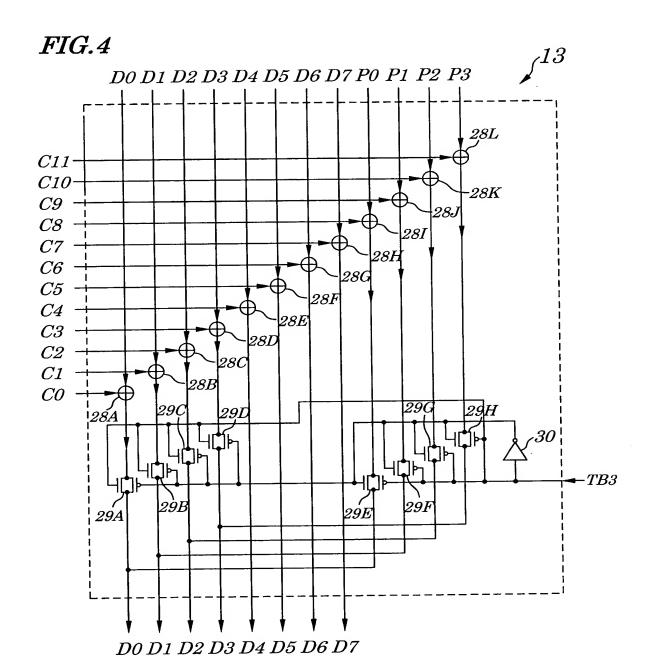




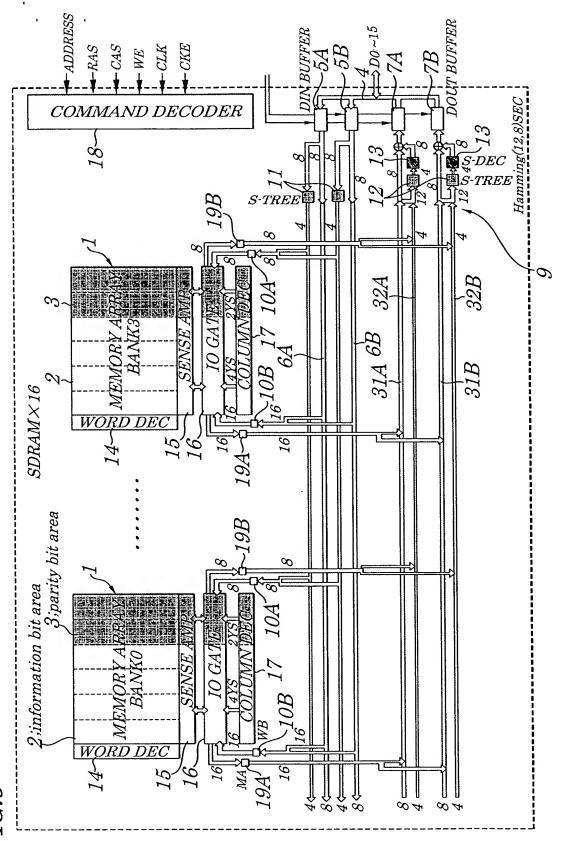


- \odot AND
- \oplus EOR



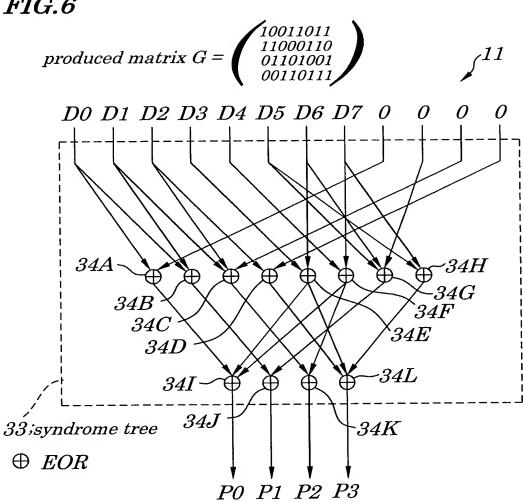


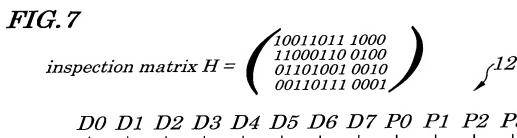
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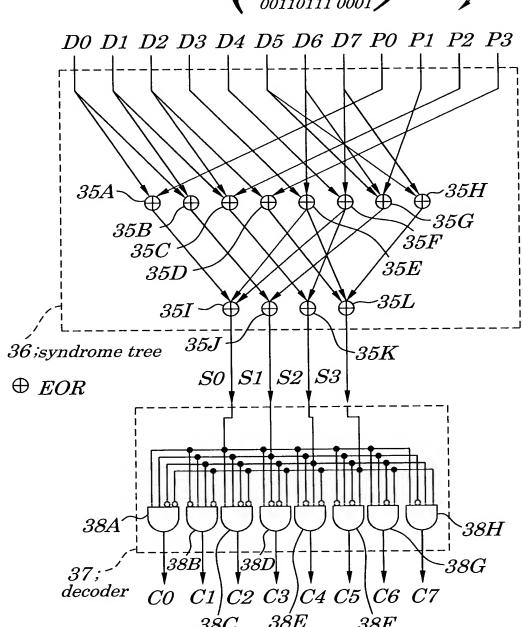


7.1G.5

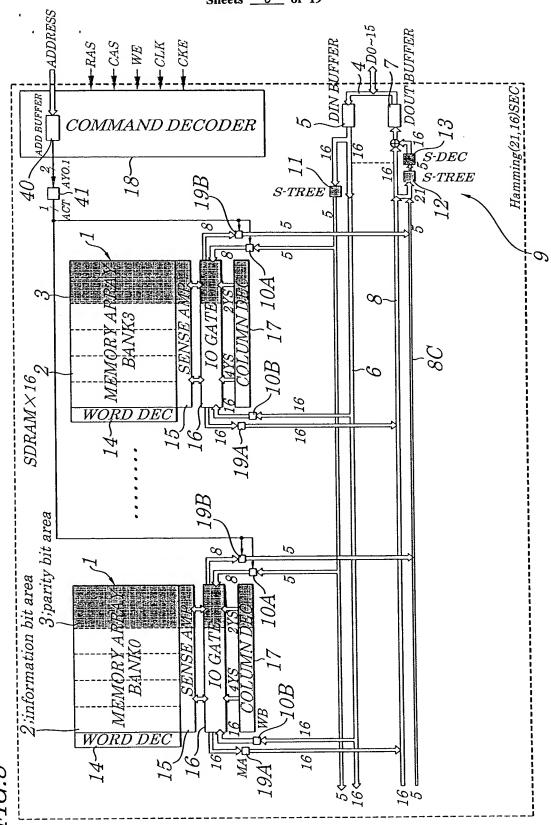




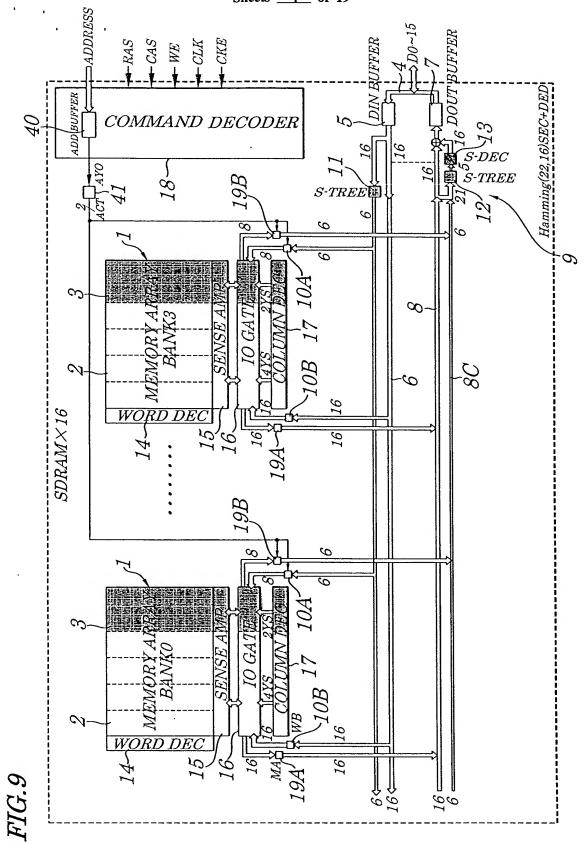




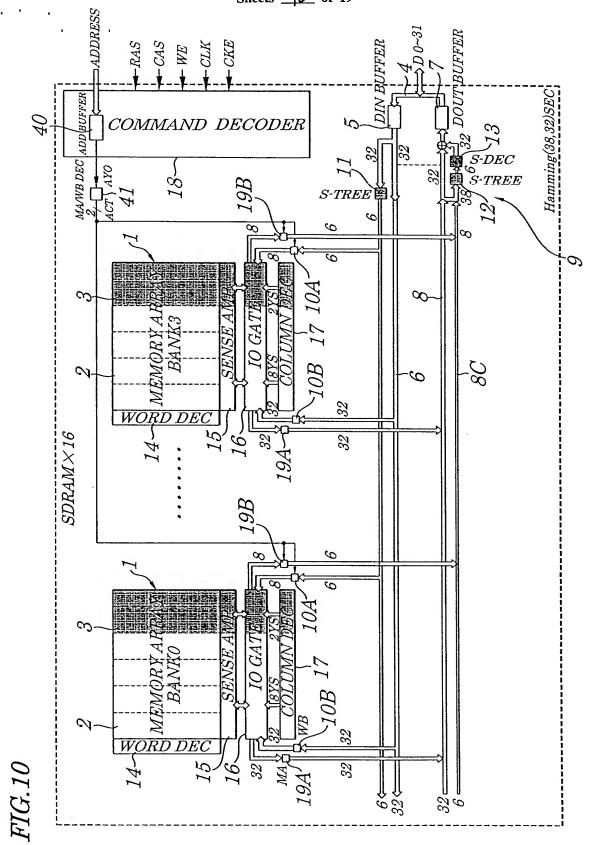
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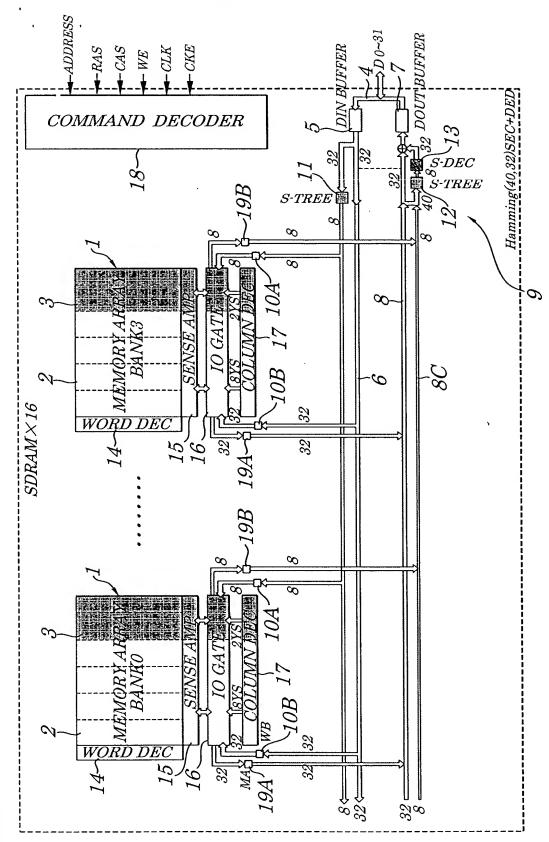
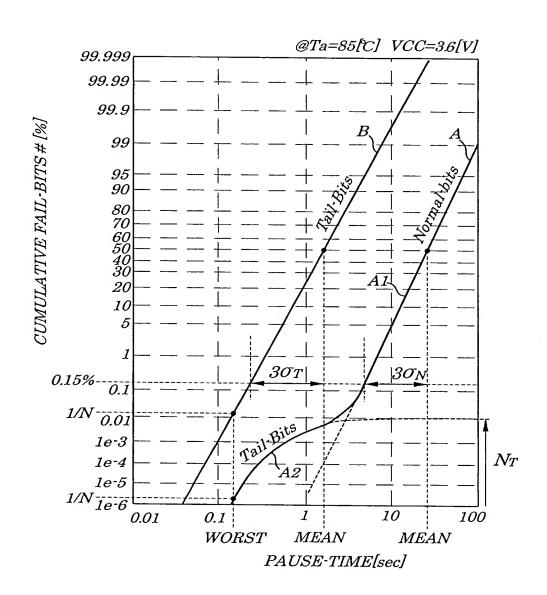
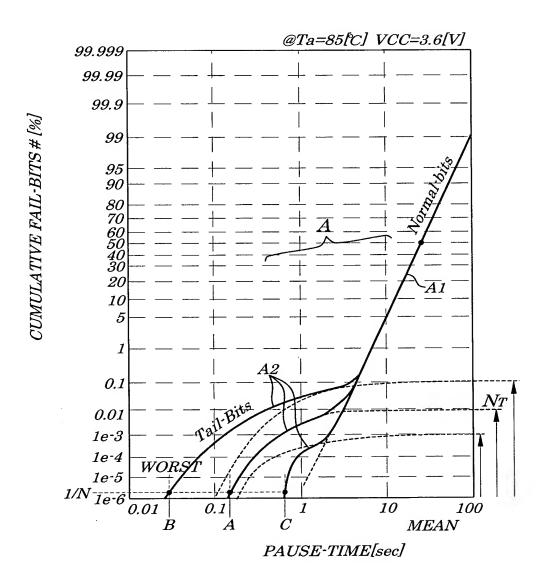
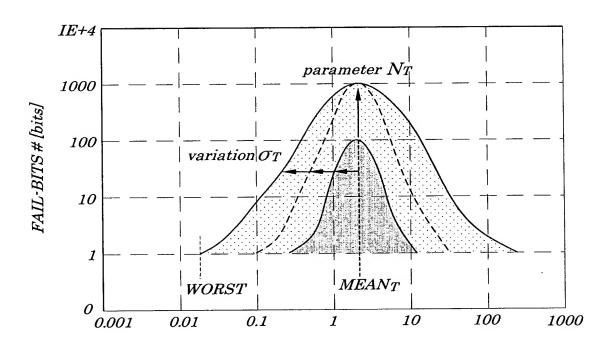


FIG.12

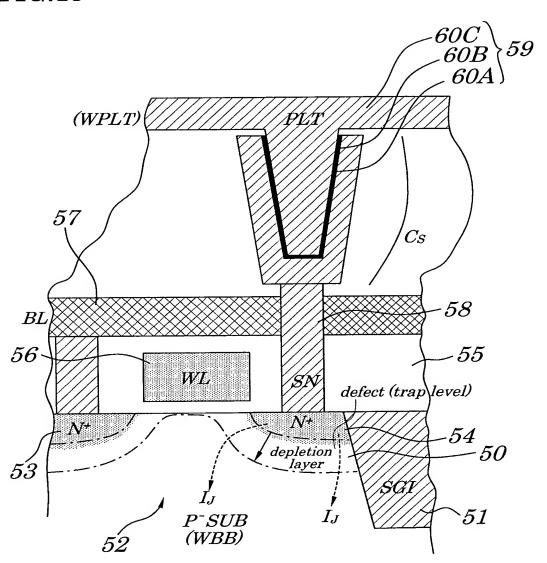






PAUSE-TIME[sec]

FIG.15



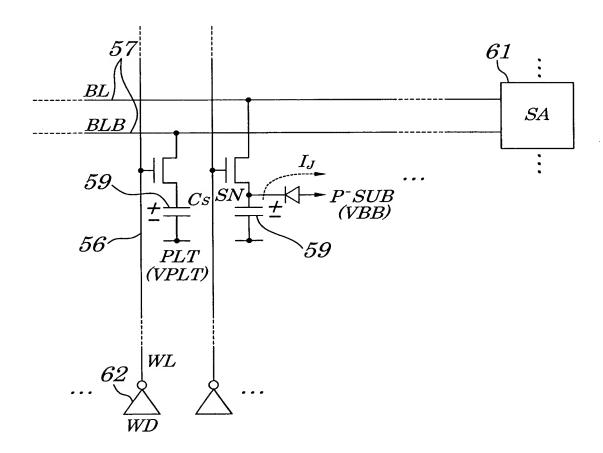
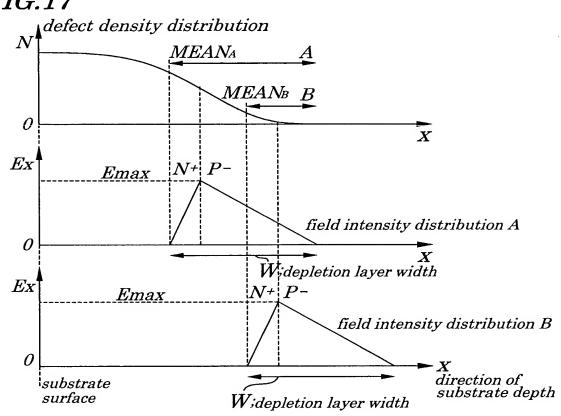
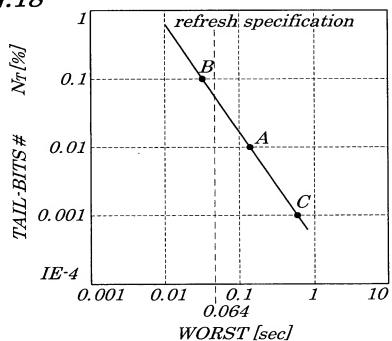
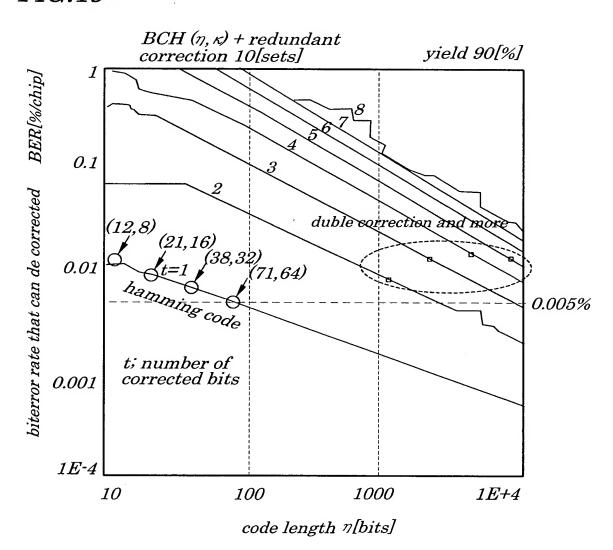


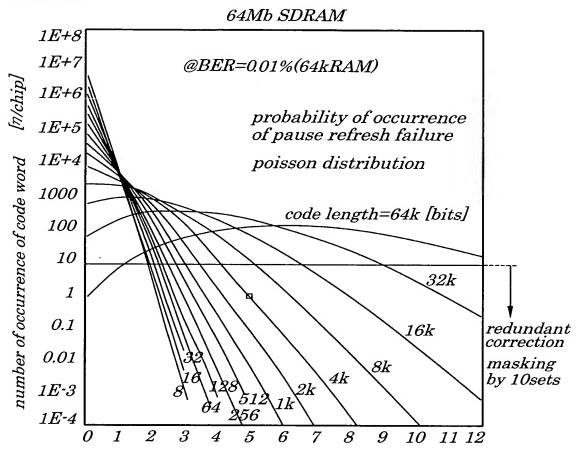
FIG.17











bit number of pause failure per one code word [bits/word]

